TOSHIBA TPS625,TPS626

TOSHIBA PHOTO DARLINGTON TRANSISTOR SILICON NPN EPITAXIAL PLANAR

TPS625, TPS626

OPTO-ELECTRONIC SWITCH HOME ELECTRIC EQUIPMENT OA EQUIPMENT

Small side view epoxy resin package

: TPS625 \cdots $I_L\!=\!0.6\text{mA}$ (MIN.) High sensitivity

 $TPS626 \cdots I_L = 0.4 mA (MIN.)$

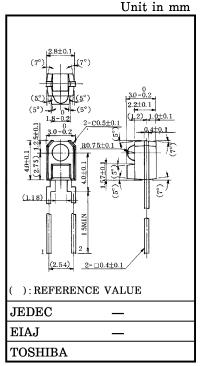
Half value angle : $\theta_{\frac{1}{2}} = \pm 15^{\circ} (TYP.)$

Visible light cut type (black package): TPS626

Optimum in combination with infrared LED TLN117 which has identical external dimensions.

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Emitter Voltage	v_{CEO}	30	V
Emitter-Collector Voltage	v_{ECO}	5	V
Collector Current	$I_{\mathbf{C}}$	40	mA
Collector Power Dissipation	PC	75	mW
Collector Power Dissipation Derating (Ta>25°C)	ΔP _C /°C	-1	mW/°C
Operating Temperature Range	T_{opr}	-25~85	°C
Storage Temperature Range	$T_{ m stg}$	-40~100	$^{\circ}\mathrm{C}$
Soldering Temperature (5s)	T _{sol}	260 (Note 1)	$^{\circ}\mathrm{C}$

Note 1: Soldering portion of lead: above 2mm from the body of the device.



Weight: 0.1g (TYP.)

OPTO-ELECTRICAL CARACTERISTICS (Ta = 25°)

CHARACTERISTIC S		SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT
Dark Current		$I_{D}(I_{CEO})$	$V_{CE} = 16V, E = 0$		-	0.03	0.25	μ A
Light Current		т	$E = 0.1 \text{mW} / \text{cm}^2$ $V_{CE} = 3 \text{V (Note 2, 3)}$	TPS625	0.6	2	_	mA
		${ m I_L}$		TPS626	0.4	1.4	_	
Collector-Emitter S Voltage	aturation	V _{CE} (sat)	$E = 0.1 \text{mW} / \text{cm}^2$ $I_L = (\text{Note 4})$		1	0.9	1.2	V
Peak Sensitivity Wavelength		$\lambda_{\mathbf{p}}$		TPS625		820	_	nm
				TPS626		870	_	11111
Half Value Angle		$\theta_{\frac{1}{2}}$				±15	_	0
Switching Time	Rise Time	$\mathrm{t_r}$	$V_{CC}=5V, I_{C}=10mA$		_	200	_	449
	Fall Time	$\mathrm{t_{f}}$	$egin{array}{l} V_{CC}\!=\!5V,\ I_{C}\!=\!10mA \ R_{L}\!=\!100\Omega \end{array}$			150		μ s

Color temperature = 2870°K, Standard Tungsten Lamp

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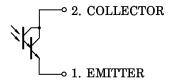
The information contained herein is subject to change without notice.

Note 3. IL Classification

RANK	IL (mA)		
KANK	TPS625	TPS626	
(A)	0.6~3.6	0.4~2.4	
(B)	2.5~15	1.7~10.2	
(C)	5MIN.	3MIN.	
_	0.6MIN.	0.4MIN.	

Note 4. TPS625: 0.3mA, TPS626: 0.2mA

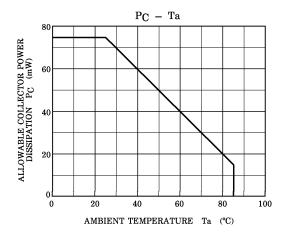
PIN CONNECTION

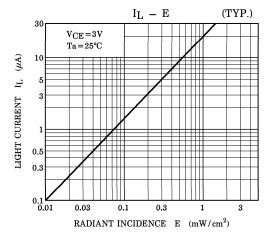


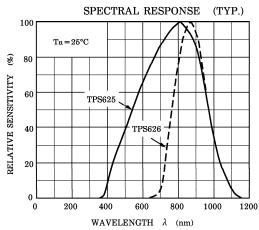
PRECAUTION

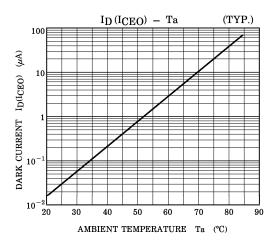
Please be careful of the followings.

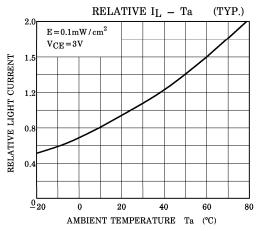
 When the lead is formed, the lead shall be formed at a distance of 2mm from the body without leaving forming stress to the body of the device.
 Soldering shall be performed after lead forming.



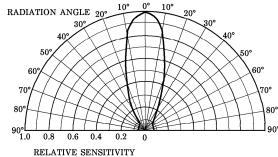












SWITCHING TIME TEST CIRCUIT

